

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10591625	CHO ET AL.
	Examiner	Art Unit
	SHIN-HON CHEN	2431

SEARCHED

Class	Subclass	Date	Examiner
380	273, 278, 264	3/23/10	S.C.

SEARCH NOTES

Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	3/23/10	S.C.

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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